

<b>Notice of References Cited</b>	Application/Control No. 10/826,299		Applicant(s)/Patent Under Reexamination LEE, SUNG-HI	
	Examiner AKWASI M. SARPONG		Art Unit 2625	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0097418 A1	07-2002	Chang et al.	358/1.13
*	B	US-2003/0037115 A1	02-2003	Tomita et al.	709/206
*	C	US-2004/0001207 A1	01-2004	Nishimura, Takeshi	358/1.2
*	D	US-6,704,122 B2	03-2004	Moro et al.	358/1.9
*	E	US-6,735,641 B1	05-2004	Kobayashi et al.	710/15
*	F	US-6,771,393 B1	08-2004	Honary, Hooman	358/426.01
*	G	US-2004/0268113 A1	12-2004	Rothman et al.	713/002
*	H	US-7,036,076 B2	04-2006	Anwar, Majid	715/255
*	I	US-7,142,321 B2	11-2006	Tomita et al.	358/1.15
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.